Optical Metrology and a Digital Optical Technologies (DOT)

Event - Optical Metrology and a Digital Optical Technologies (DOT) ↻

Title	Optical Metrology and a Digital Optical Technologies (DOT)
When	Mo, 26. Juni 2017 - Do, 29. Juni 2017

Description

We would like to draw your attention to our well-known 2-year SPIE conference

Optical Metrology and a new SPIE conference Digital Optical Technologies (DOT)

both co-located with Laser Munich in Munich, Germany, June 26-29, 2017, and take this opportunity to invite you to submit and present your latest research at this high-quality meetings.

The conferences links can be found by following links:

http://spie.org/conferences-and-exhibitions/optical-metrology

https://spie.org/conferences-and-exhibitions/digital-optical-technologies

Venue - Neue Messe München

Location	Neue Messe München
Street	Am Messesee
Postcode	81829
City	München
County	Bayern
Country	DE
Website	http://www.messe-muenchen.de